

**Search Notes**

Application/Control No.

10/617,322

Examiner

Tianjie Chen

Applicant(s)/Patent under  
Reexamination

DINAN ET AL.

Art Unit

2652

**SEARCHED**

Class	Subclass	Date	Examiner
Updated		7/11/2005	TJ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR